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Supplementary Information for Layer-resolving ability and model analysis of LIBS for multilayer samples with a four-layer structure under different focusing conditions (Part 2 of 3)

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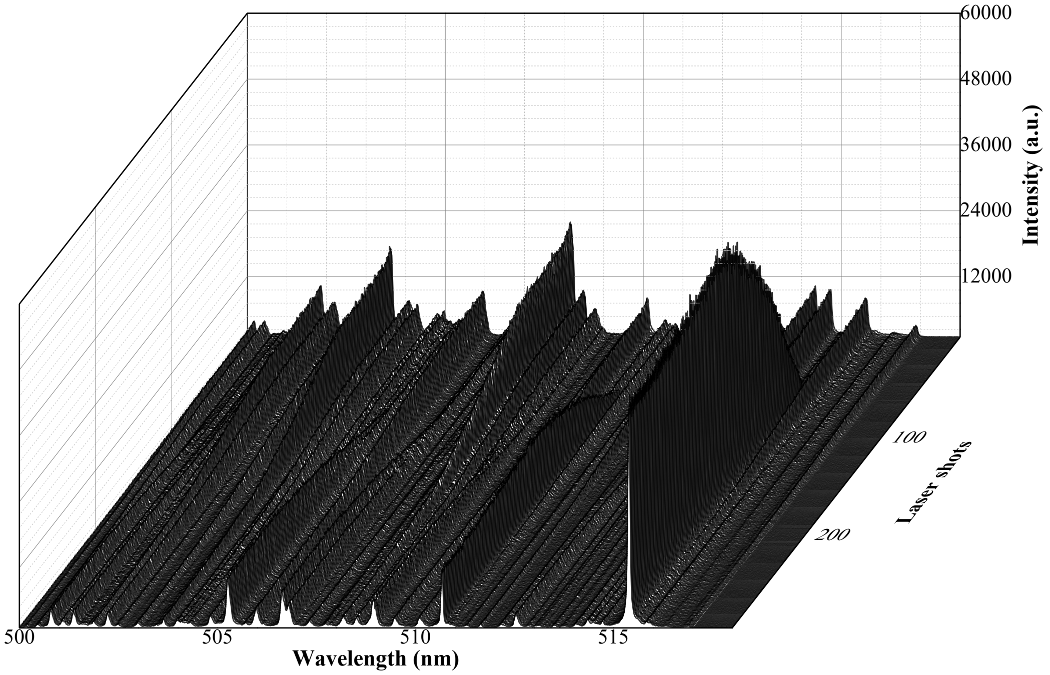

Figure. S6. Typical spectra of sample S2 at ΔL = 9 cm.

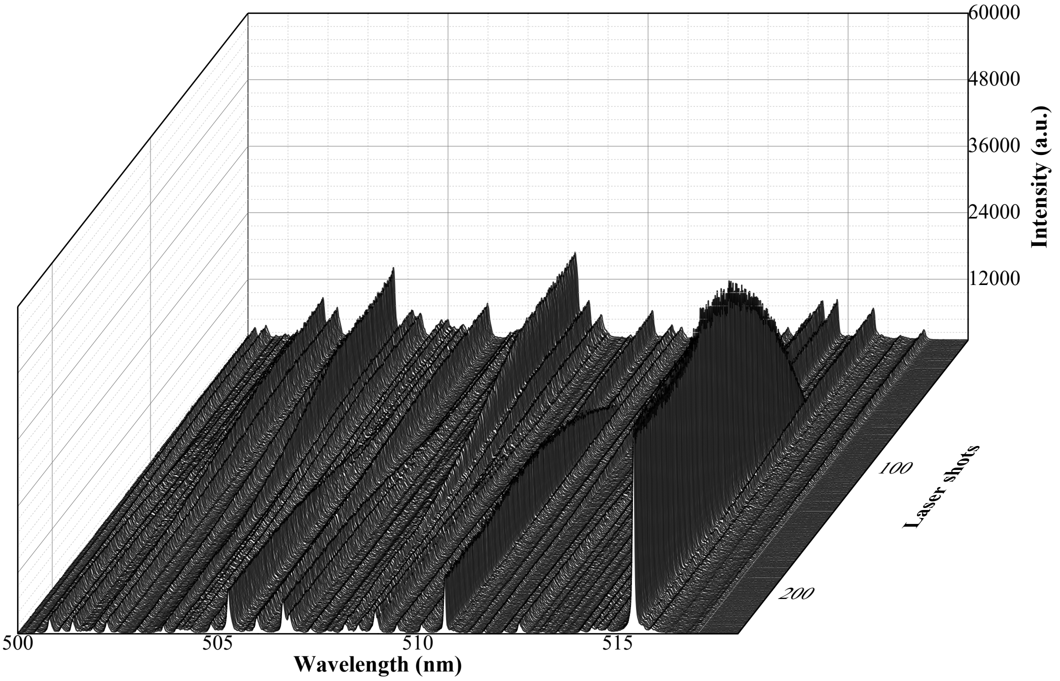

Figure. S7. Typical spectra of sample S2 at ΔL = 8 cm.

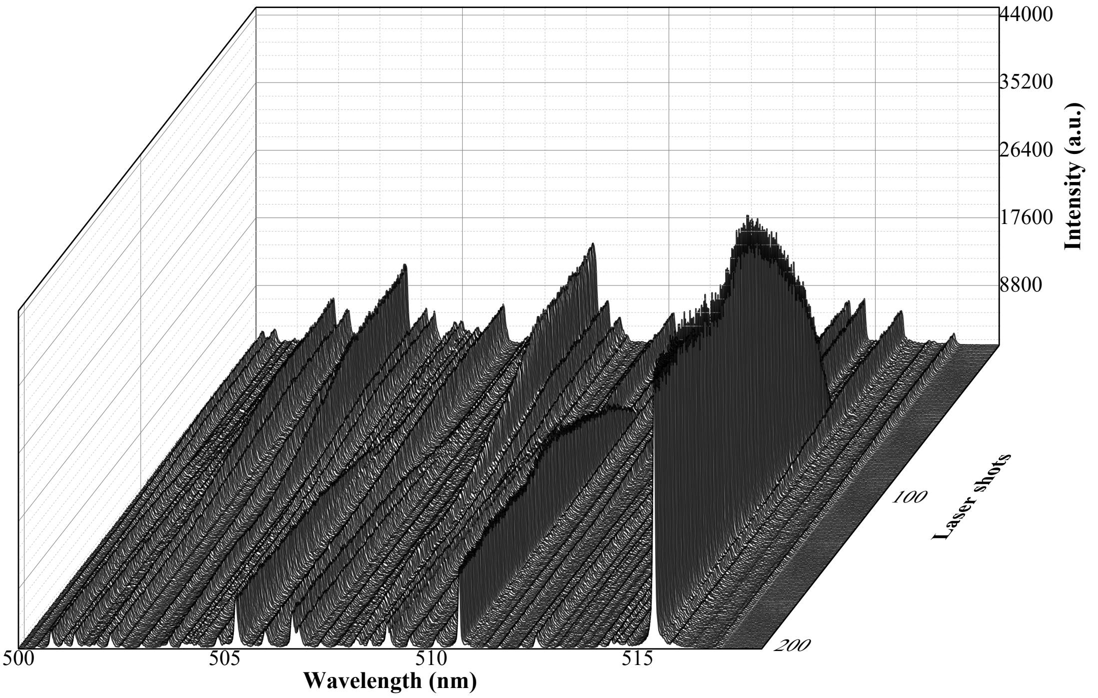

Figure. S8. Typical spectra of sample S2 at ΔL = 7 cm.

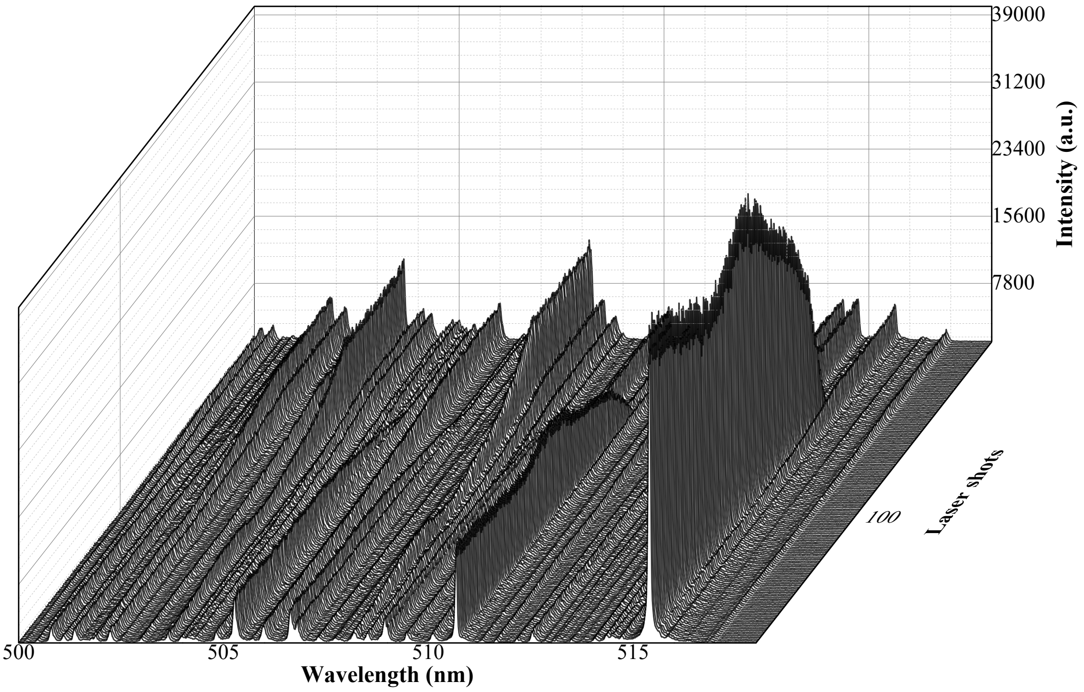

Figure. S9. Typical spectra of sample S2 at ΔL = 6 cm.

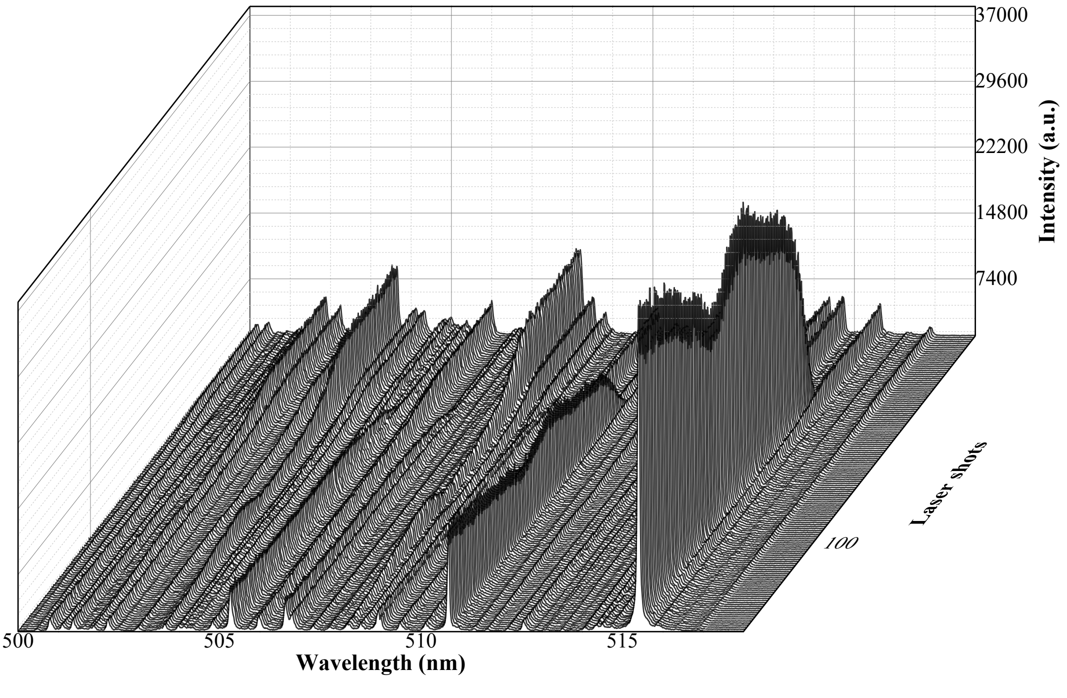

Figure. S10. Typical spectra of sample S2 at ΔL = 5 cm.